500.42015VX1

February 14, 2005

## UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants:

MIYA et al

Serial No.:

10/781,689

Filed:

February 20, 2004

For:

Diagnosis Method For Semiconductor Processing Apparatus

Group:

1763

Examiner:

P. Hassanzadeh

## CITATION OF DOCUMENTS UNDER 37 CFR 1.56

Mail Stop: DD

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application, applicants are submitting herewith copies of the non-US documents listed in the attached form equivalent to Form PTO-1449 for the Examiner's consideration.

It is respectfully requested that these documents be considered by the Examiner.

Please charge any shortage in the fees due in connection with the filing of this paper, including extension of time fees, to the deposit account of Antonelli, Terry, Stout & Kraus Deposit Account No. 01-2135 (Case: 500.42015VX1), and please credit any excess fees to such deposit account.

Respectfully submitted,

ANTONELLI, TERRY, STOUT & KRAUS, LLP

Melvin Krauš

Registration No. 22,466

MK/jla (703) 312-6600 Attachments

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Date Considered

Examiner